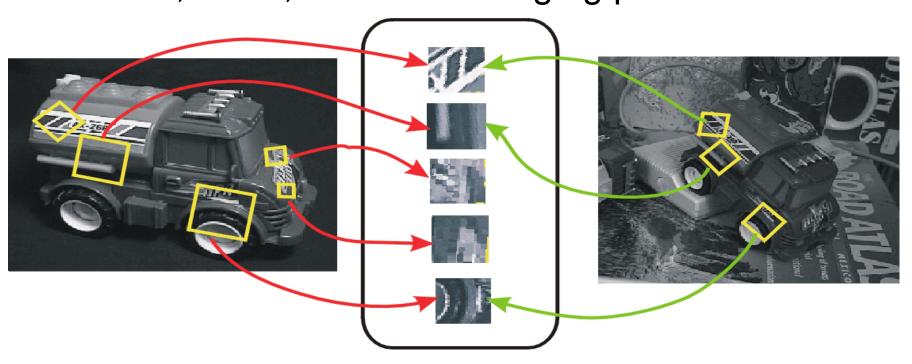
Invariant Local Features

•Image content is transformed into local feature coordinates that are invariant to translation, rotation, scale, and other imaging parameters



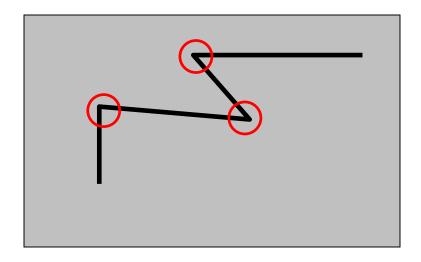
Features Descriptors

More motivation...

- Feature points are used for:
 - Image alignment (homography, fundamental matrix)
 - -3D reconstruction
 - Motion tracking
 - Object recognition
 - Indexing and database retrieval
 - Robot navigation
 - -... other

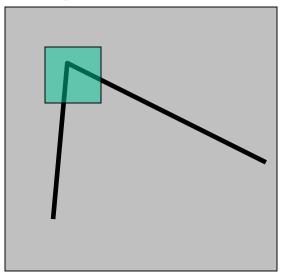
Corner detector

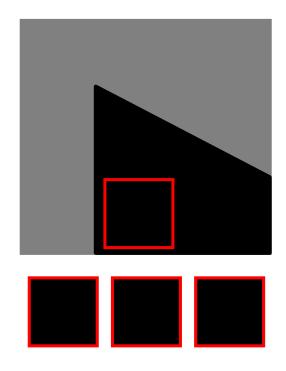
 C.Harris, M.Stephens. "A Combined Corner and Edge Detector". 1988



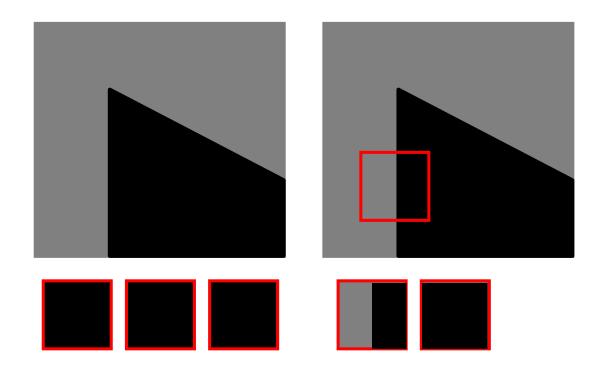
The Basic Idea

- We should easily recognize the point by looking through a small window
- Shifting a window in any direction should give a large change in intensity

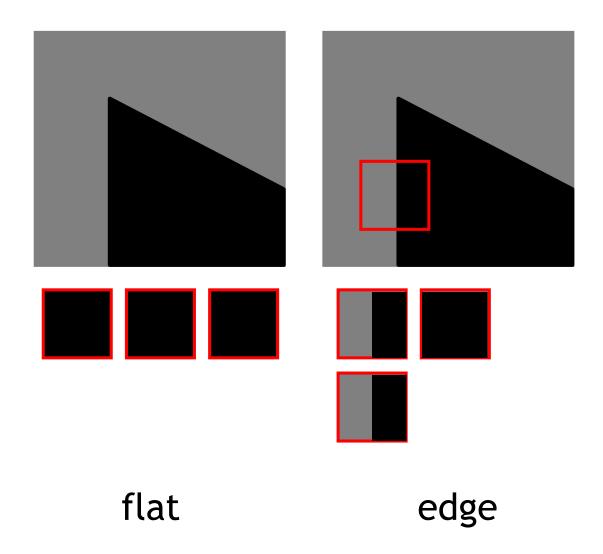


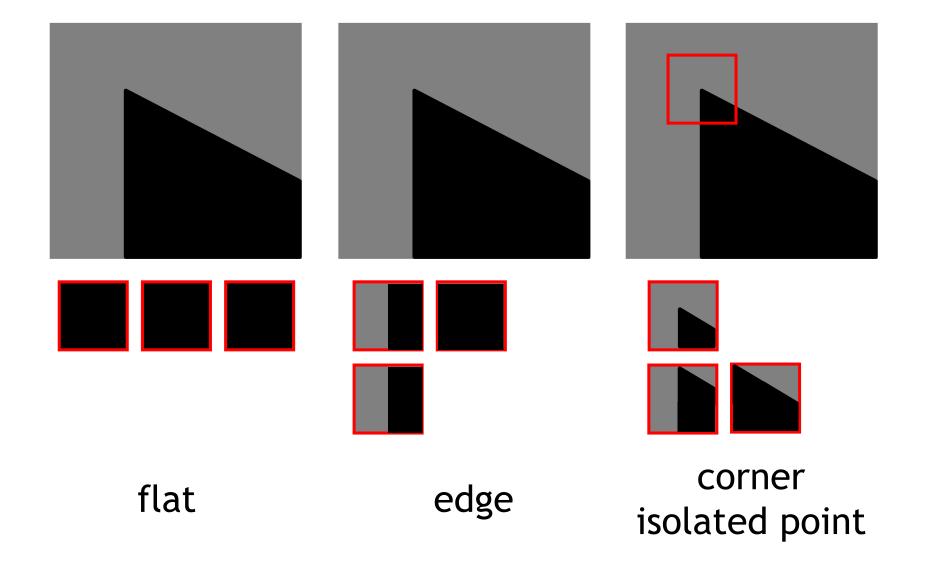


flat

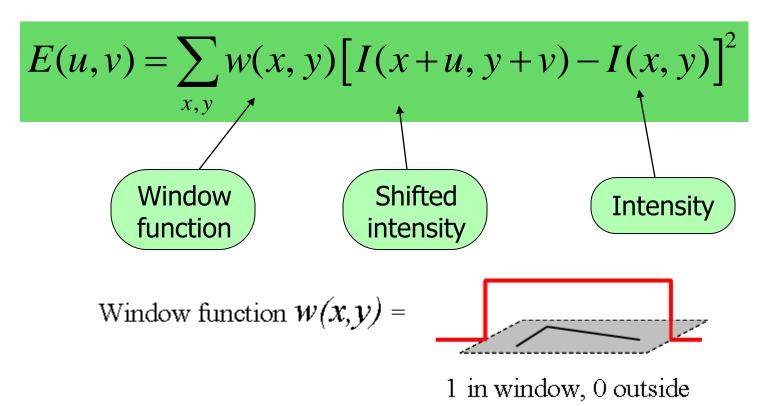


flat





Change of intensity for the shift [*u,v*]:



Four shifts: (u,v) = (1,0), (1,1), (0,1), (-1, 1)Look for local maxima in $min\{E\}$

When does this idea fail?

Problems of Moravec detector

- Only a set of shifts at every 45 degree is considered
- Noisy response due to a binary window function
- Only minimum of E is taken into account

⇒Harris corner detector (1988) solves these problems.

Noisy response due to a binary window function

> Use a Gaussian function

$$w(x,y) = \exp\left(-\frac{(x^2 + y^2)}{2\sigma^2}\right)$$

Window function
$$w(x,y) =$$

Gaussian

Only a set of shifts at every 45 degree is considered

Consider all small shifts by Taylor's expansion

$$E(u,v) = \sum_{x,y} w(x,y) [I(x+u,y+v) - I(x,y)]^{2}$$

$$= \sum_{x,y} w(x,y) [I_{x}u + I_{y}v + O(u^{2},v^{2})]^{2}$$

$$E(u,v) = Au^{2} + 2Cuv + Bv^{2}$$

$$A = \sum_{x,y} w(x,y) I_{x}^{2}(x,y)$$

$$B = \sum_{x,y} w(x,y) I_{y}^{2}(x,y)$$

$$C = \sum_{x,y} w(x,y) I_{x}(x,y) I_{y}(x,y)$$

Equivalently, for small shifts [u,v] we have a *bilinear* approximation:

$$E(u,v) \cong \begin{bmatrix} u,v \end{bmatrix} \quad M \quad \begin{bmatrix} u\\v \end{bmatrix}$$

, where M is a 2×2 matrix computed from image derivatives:

$$M = \sum_{x,y} w(x,y) \begin{bmatrix} I_x^2 & I_x I_y \\ I_x I_y & I_y^2 \end{bmatrix}$$

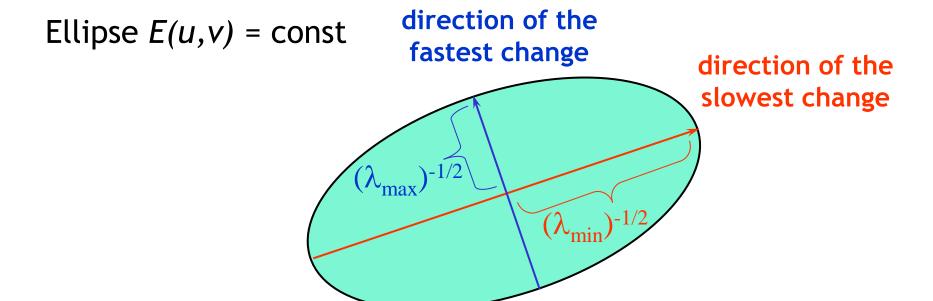
Only minimum of E is taken into account

>A new corner measurement

Intensity change in shifting window: eigenvalue analysis

$$E(u,v) \cong [u,v]$$
 M $\begin{bmatrix} u \\ v \end{bmatrix}$ λ_1, λ_2 – eigenvalues of M

$$\lambda_1, \lambda_2$$
 – eigenvalues of M



Classification of image points using eigenvalues of *M*:

edge $\lambda_2 \gg \lambda_1$ Corner λ_1 and λ_2 are large, $\lambda_1 \sim \lambda_2$; E increases in all directions flat

 λ_1 and λ_2 are small; E is almost constant in all directions

 λ_1

Measure of corner response:

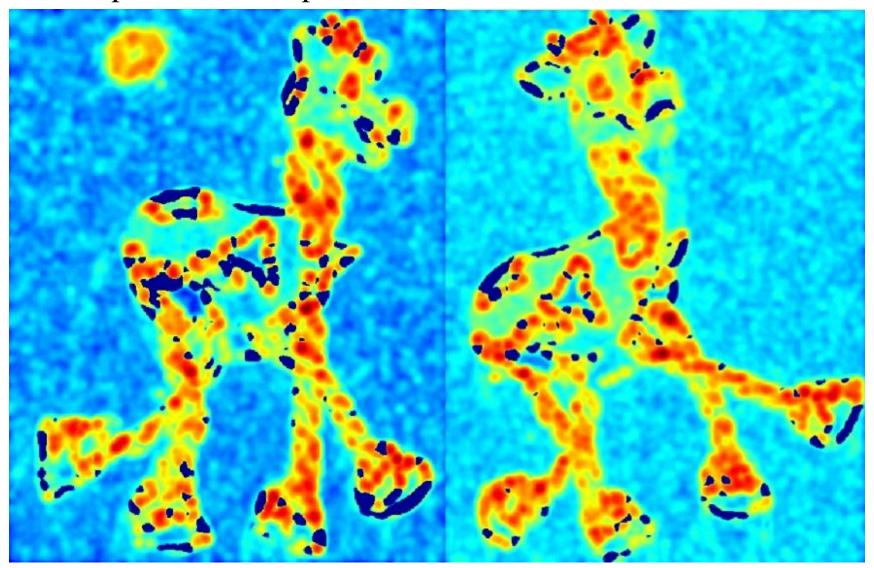
$$R = \frac{\lambda_1 \lambda_2}{\lambda_1 + \lambda_2} = \frac{\det M}{\operatorname{Trace} M}$$

Harris Detector

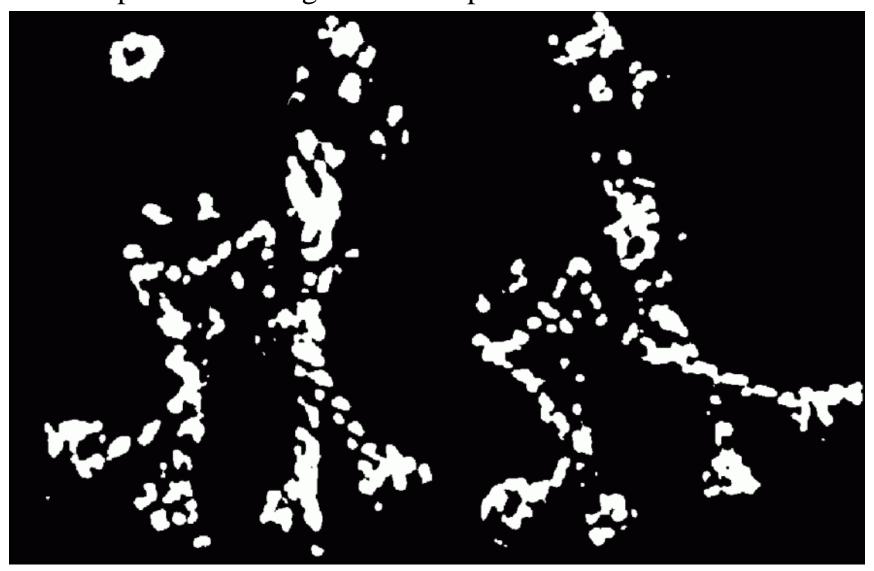
- The Algorithm:
 - Find points with large corner response function R (R > threshold)
 - -Take the points of local maxima of R



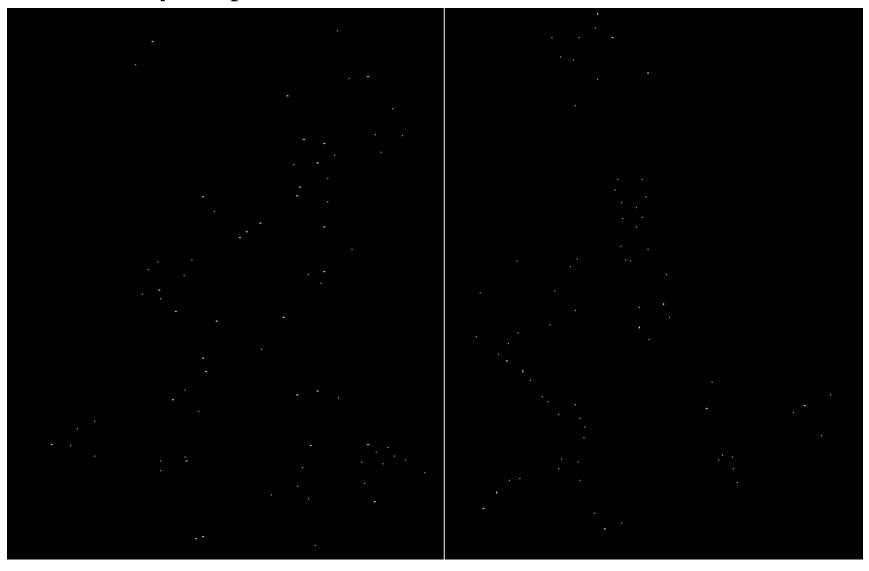
Compute corner response R



Find points with large corner response: *R*>threshold



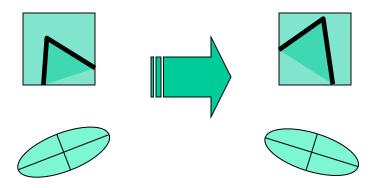
Take only the points of local maxima of R





Harris Detector: Some Properties

Rotation invariance



Ellipse rotates but its shape (i.e. eigenvalues) remains the same

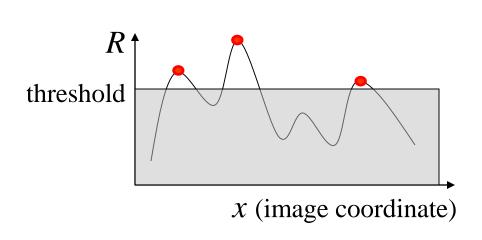
Corner response R is invariant to image rotation

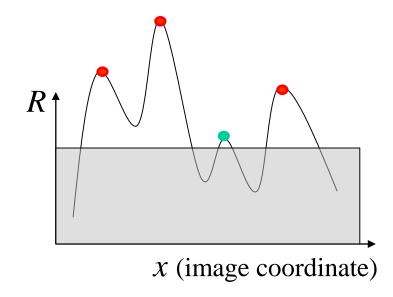
Harris Detector: Some Properties

Partial invariance to affine intensity change

✓ Only derivatives are used => invariance to intensity shift $I \rightarrow I + b$

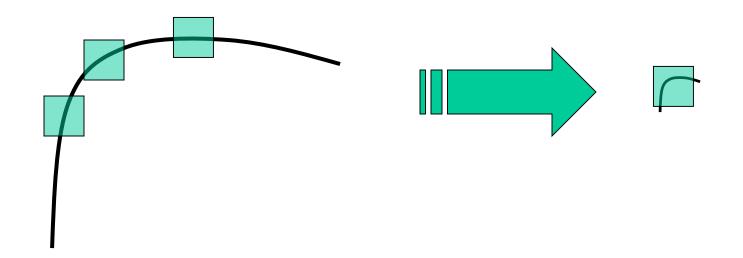
✓ Intensity scale: $I \rightarrow a I$





Harris Detector: Some Properties

But: non-invariant to image scale!



All points will be classified as edges

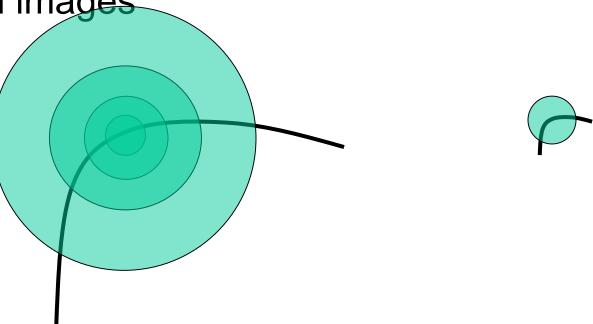
Corner!

Scale Invariant Detection

 Consider regions (e.g. circles) of different sizes around a point

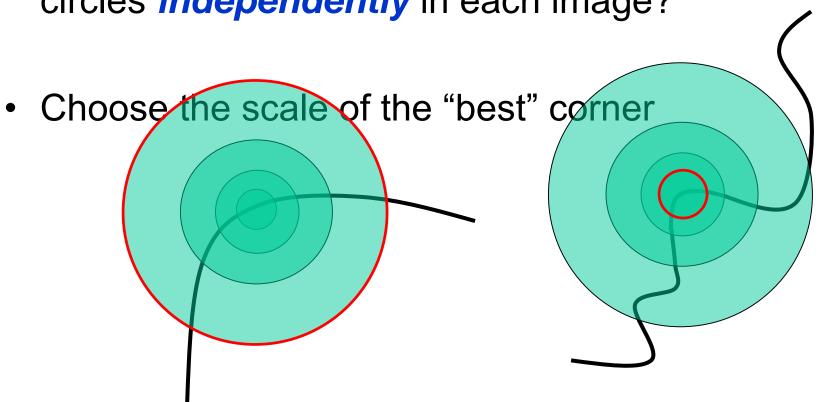
Regions of corresponding sizes will look the same





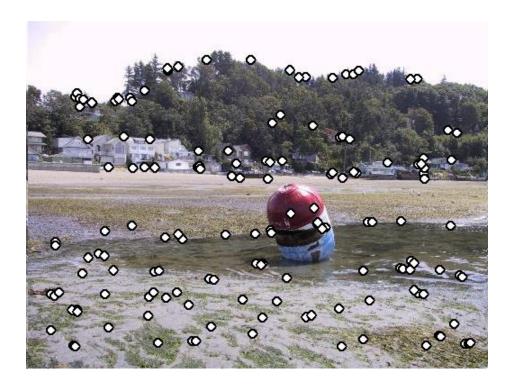
Scale Invariant Detection

 The problem: how do we choose corresponding circles independently in each image?



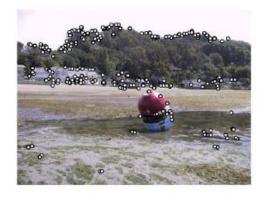
Feature selection

Distribute points evenly over the image



Adaptive Non-maximal Suppression

- Desired: Fixed # of features per image
 - Want evenly distributed spatially...
 - Sort ponts by non-maximal suppression radius [Brown, Szeliski, Winder, CVPR'05]



(a) Strongest 250



(b) Strongest 500



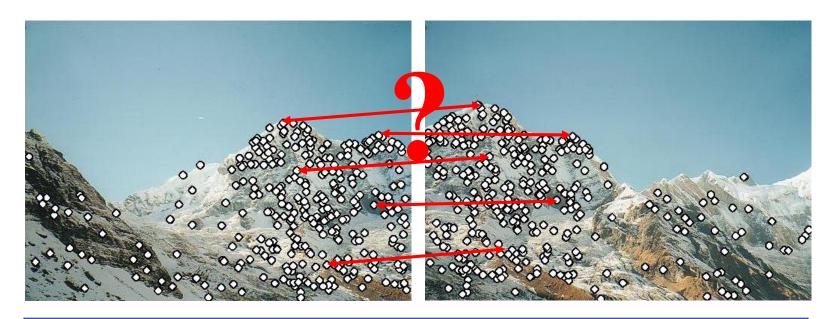
(c) ANMS 250, r = 24



(d) ANMS 500, r = 16

Feature descriptors

- We know how to detect points
- Next question: How to match them?



Point descriptor should be:

1. Invariant

2. Distinctive

Descriptors Invariant to Rotation

Find local orientation

Dominant direction of gradient





• Extract image patches relative to this orientation

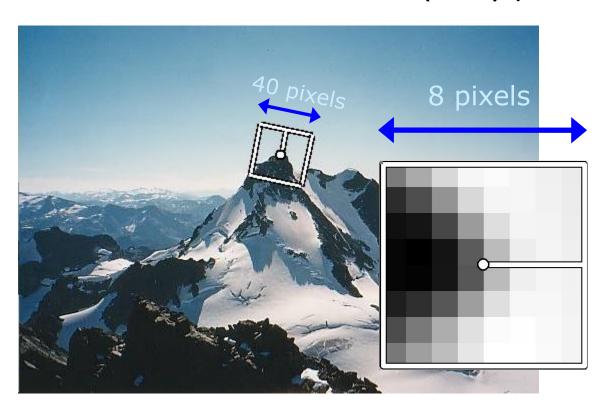
Descriptor Vector

- Rotation Invariant Frame
- Orientation = blurred gradient



MOPS descriptor vector

- 8x8 oriented patch
 - Sampled at 5 x scale
- Bias/gain normalisation: $I' = (I \mu)/\sigma$



Detections at multiple scales

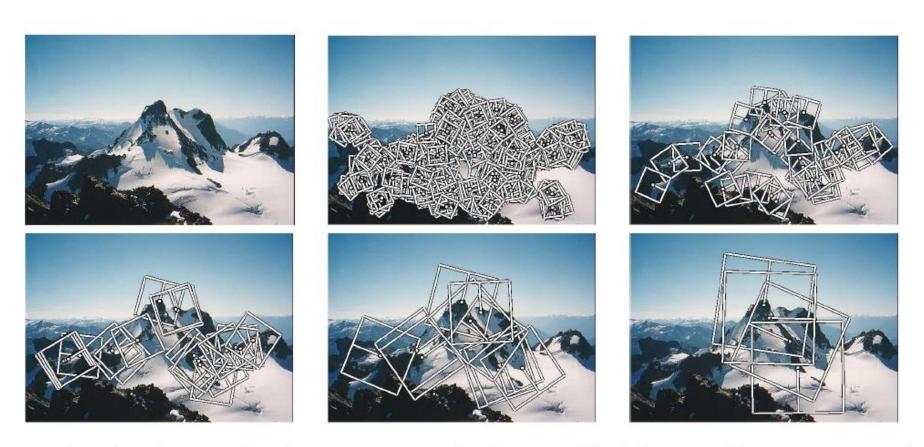


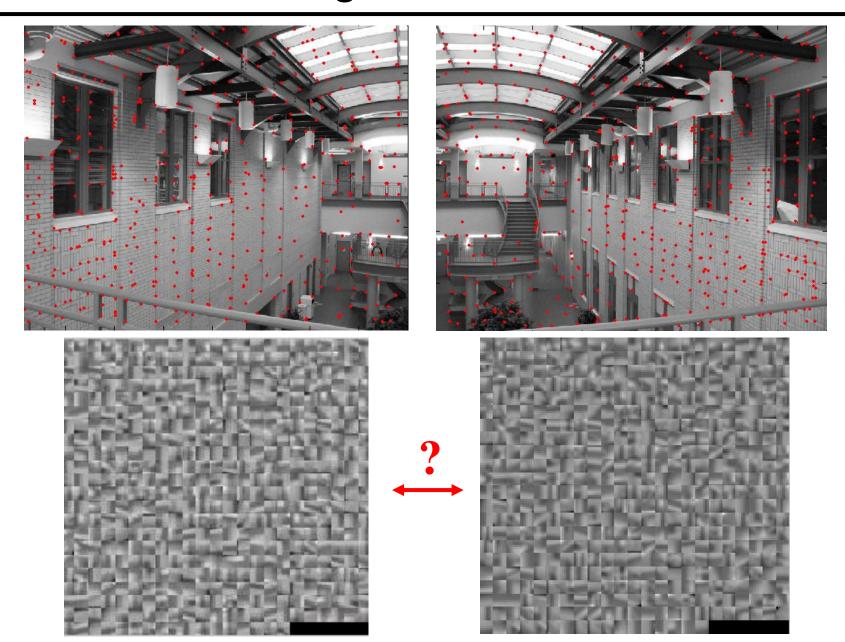
Figure 1. Multi-scale Oriented Patches (MOPS) extracted at five pyramid levels from one of the Matier images. The boxes show the feature orientation and the region from which the descriptor vector is sampled.

Multi-Scale Oriented Patches (Summary)

Interest points

- Multi-scale Harris corners
- Orientation from blurred gradient
- Geometrically invariant to rotation
- Descriptor vector
 - Bias/gain normalized sampling of local patch (8x8)
 - Photometrically invariant to affine changes in intensity
- [Brown, Szeliski, Winder, CVPR'2005]

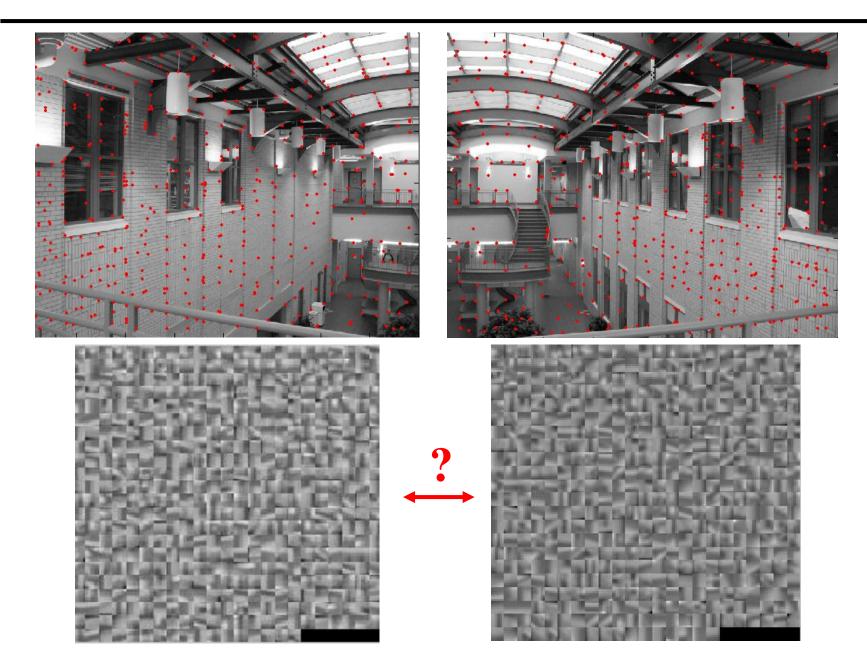
Feature matching



Feature matching

- Exhaustive search
 - for each feature in one image, look at all the other features in the other image(s)
- Hashing
 - compute a short descriptor from each feature vector, or hash longer descriptors (randomly)
- Nearest neighbor techniques
 - kd-trees and their variants

What about outliers?



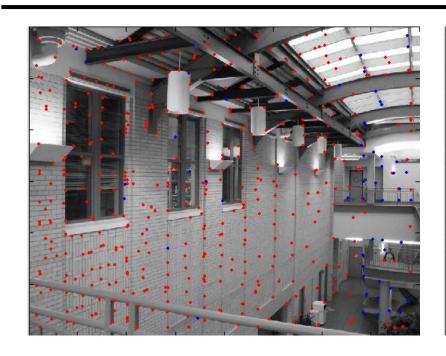
Feature-space outlier rejection

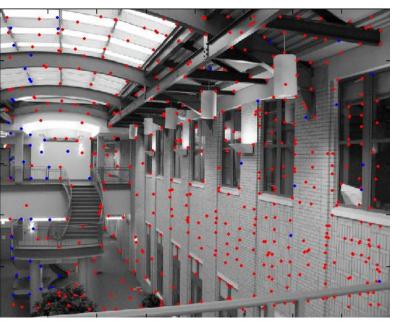
- Let's not match all features, but only these that have "similar enough" matches?
- How can we do it?
 - SSD(patch1,patch2) < threshold
 - How to set threshold?

Feature-space outlier rejection

- A better way [Lowe, 1999]:
 - 1-NN: SSD of the closest match
 - 2-NN: SSD of the second-closest match
 - Look at how much better 1-NN is than 2-NN, e.g.
 1-NN/2-NN
 - That is, is our best match so much better than the rest?

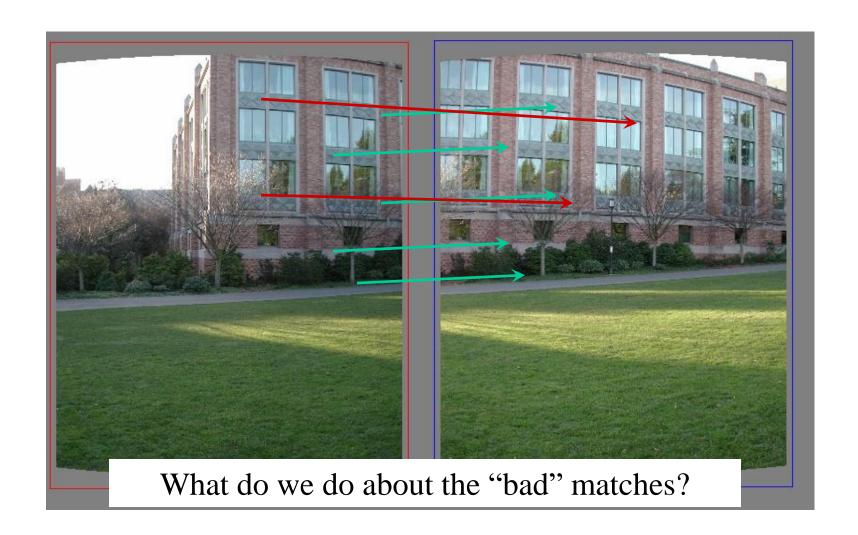
Feature-space outliner rejection



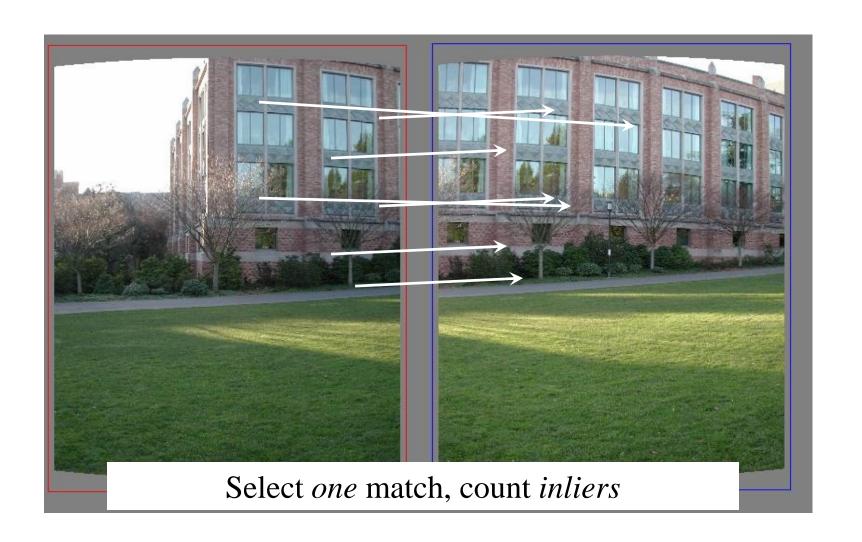


- Can we now compute H from the blue points?
 - No! Still too many outliers...
 - What can we do?

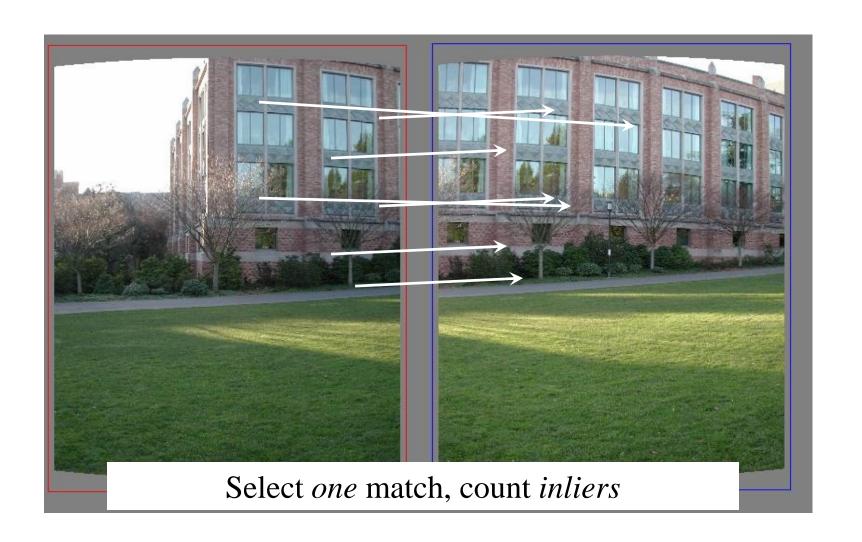
Matching features



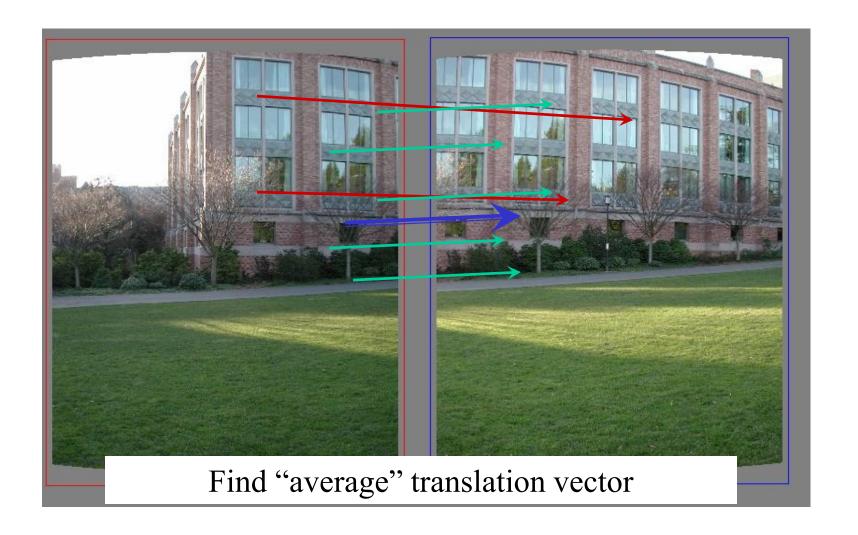
RAndom SAmple Consensus



RAndom SAmple Consensus



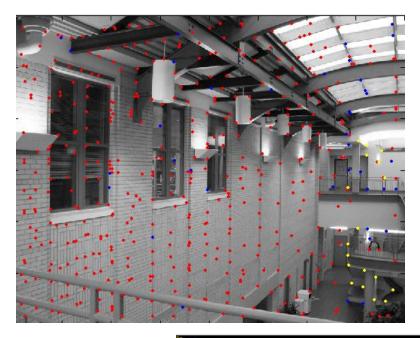
Least squares fit

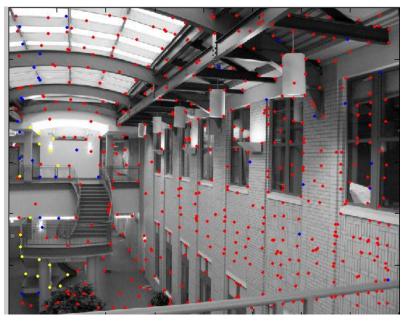


RANSAC for estimating homography

- RANSAC loop:
- 1. Select four feature pairs (at random)
- 2. Compute homography H (exact)
- 3. Compute *inliers* where $SSD(p_i', \mathbf{H} p_i) < \varepsilon$
- 4. Record the largest set of inliers so far
- Re-compute least-squares H estimate on the largest set of the inliers

RANSAC







RANSAC in general

- RANSAC = Random Sample Consensus
- an algorithm for robust fitting of models in the presence of many data outliers
- Compare to robust statistics

• Given N data points x_i , assume that mjority of them are generated from a model with parameters Θ , try to recover Θ .

RANSAC algorithm

- Run k times: How many times?
 - (1) draw n samples randomly How big?
 Smaller is better
 - (2) fit parameters Θ with these n samples
 - (3) for each of other N-n points, calculate its distance to the fitted model, count the number of inlier points, c

Output Θ with the largest c

How to define? Depends on the problem.

How to determine k

n: number of samples drawn each iteration

p: probability of real inliers

P: probability of at least 1 success after k trials

$$\dot{P} = 1 - (1 - p^n)^k$$

n samples are all inliers

a failure

failure after k trials

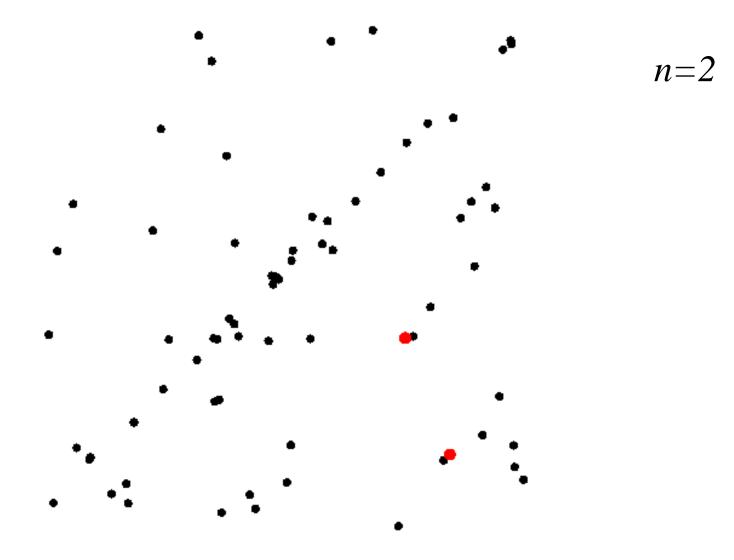
$$k = \frac{\log(1-P)}{\log(1-p^n)}$$

n	p	k
3	0.5	35
6	0.6	97
6	0.5	293

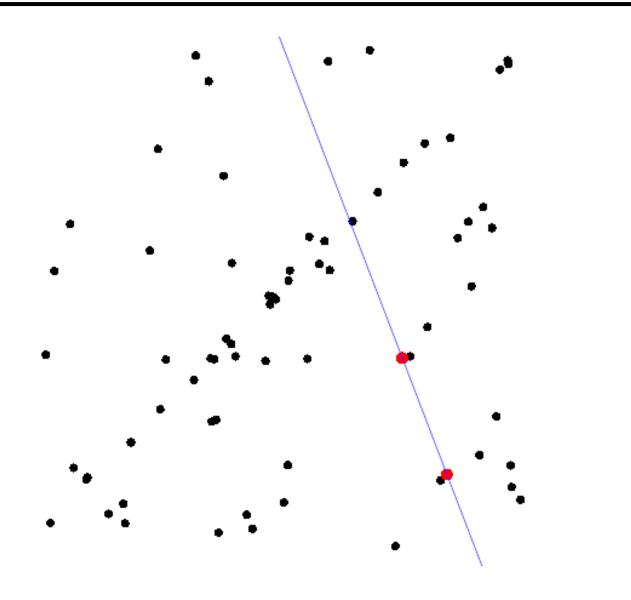
Example: line fitting



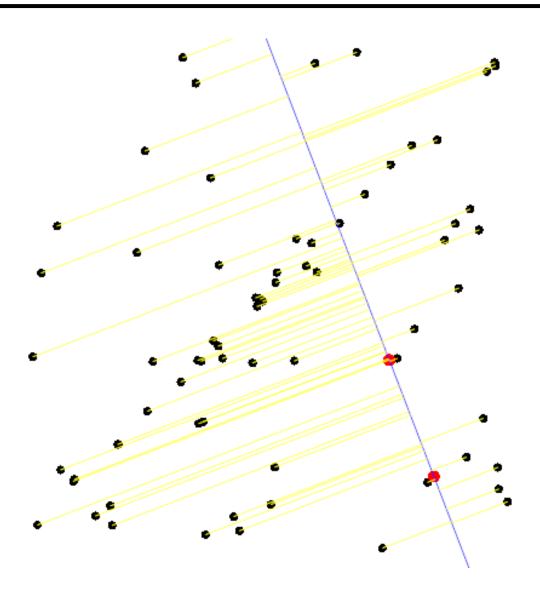
Example: line fitting



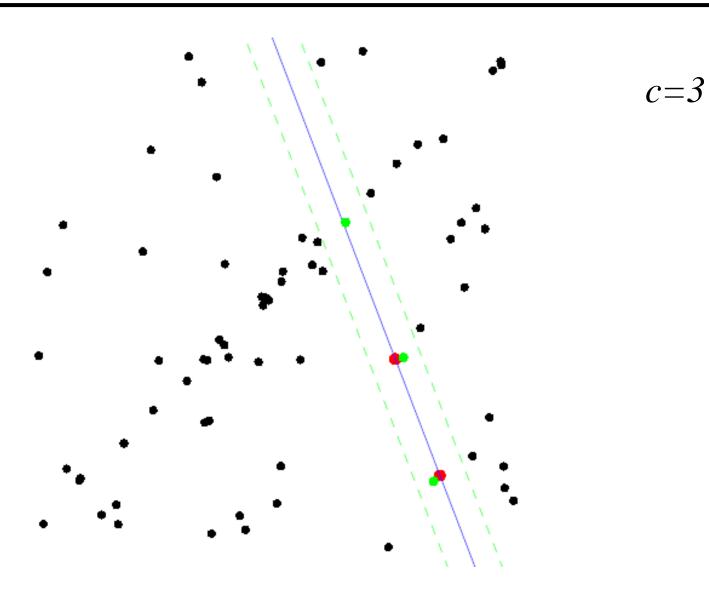
Model fitting



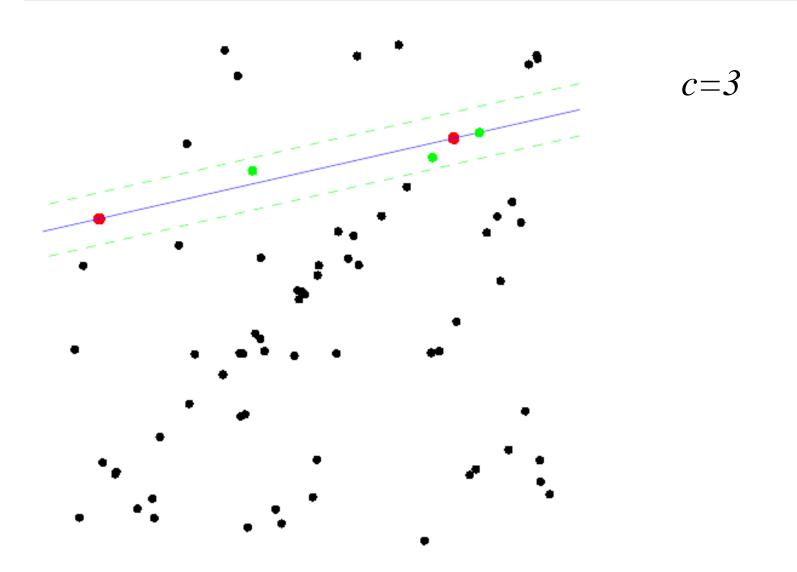
Measure distances



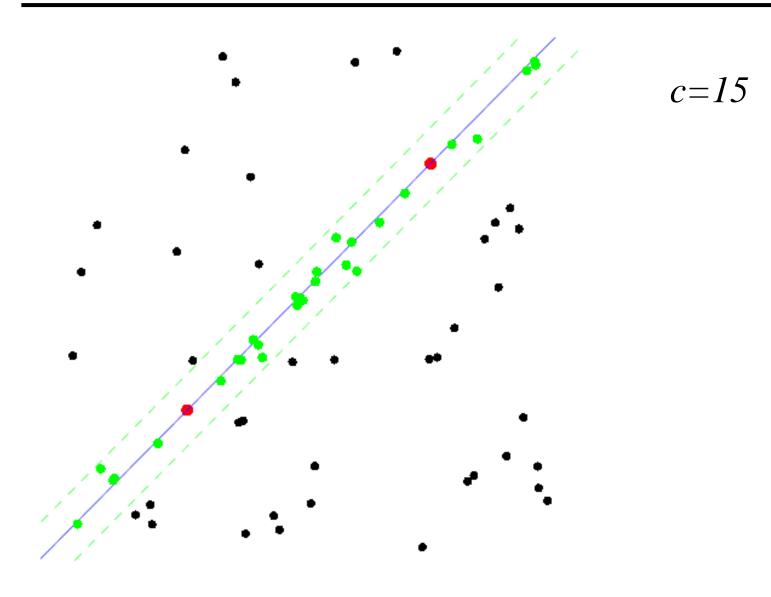
Count inliers



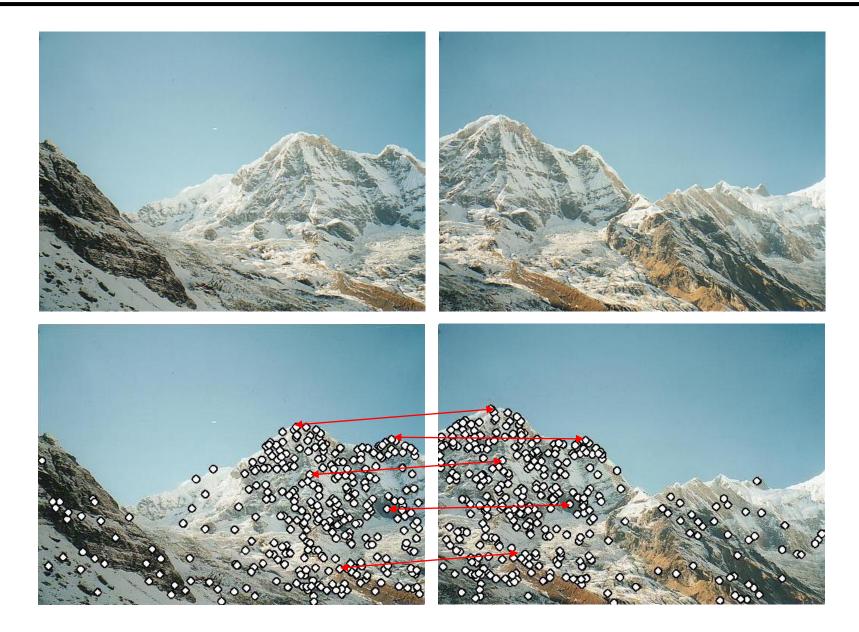
Another trial

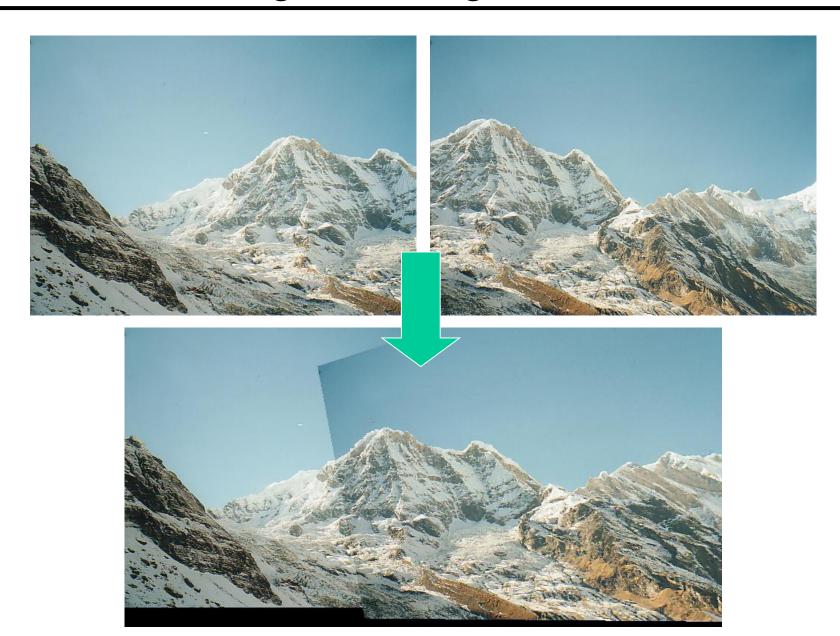


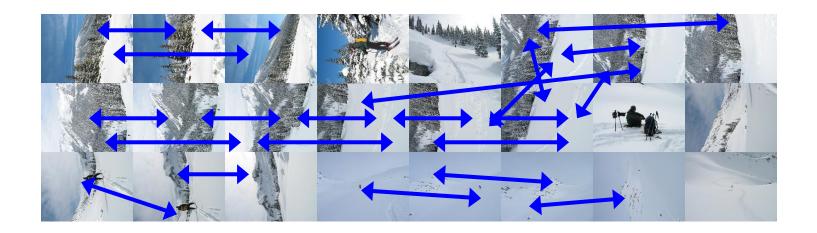
The best model

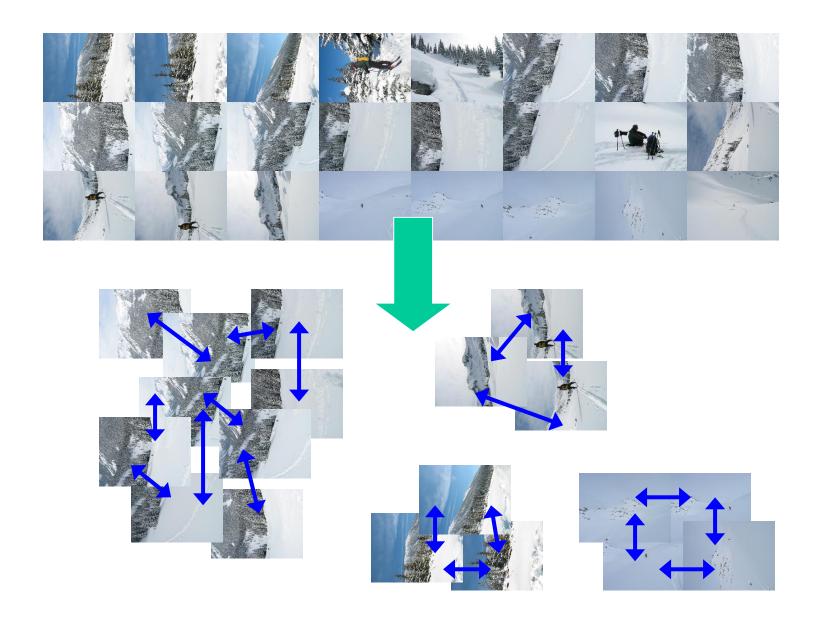


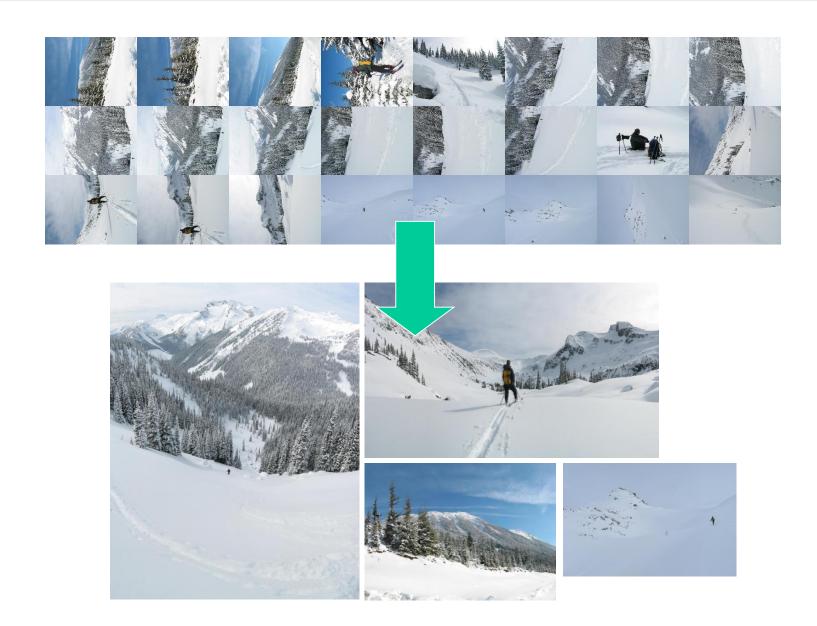
Applications



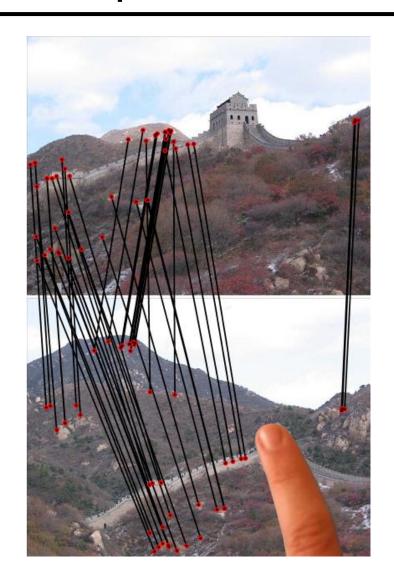








Correspondence Results





Chum & Matas 2005

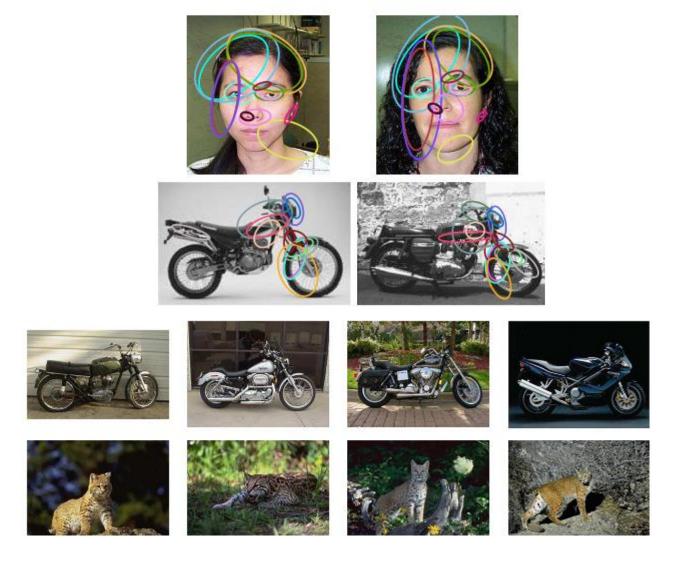
Object Recognition Results



Object Recognition Results

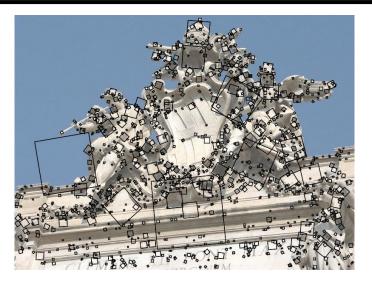


Object Classification Results



Grauman & Darrell 2006, Dorko & Schmid 2004

Geometry Estimation Results









Snavely, Seitz, & Szeliski 2006

Object Tracking Results



Robotics: Sony Aibo

SIFT is used for

- Recognizing charging station
- Communicating with visual cards
- Teaching object recognition

> soccer

